

December 2008

FDS8958B

Dual N & P-Channel PowerTrench[®] MOSFET Q1-N-Channel: 30 V, 6.4 A, 26 m Ω Q2-P-Channel: -30 V, -4.5 A, 51 m Ω

Features

Q1: N-Channel

- Max $r_{DS(on)} = 26 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 6.4 \text{ A}$
- Max $r_{DS(on)}$ = 39 m Ω at V_{GS} = 4.5 V, I_D = 5.2 A

Q2: P-Channel

- Max $r_{DS(on)}$ = 51 m Ω at V_{GS} = -10 V, I_D = -4.5 A
- Max $r_{DS(on)}$ = 80 m Ω at V_{GS} = -4.5 V, I_D = -3.3 A
- HBM ESD protection level > 3.5 kV (Note 3)
- RoHS Compliant



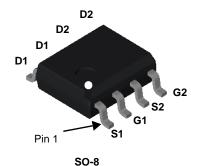
General Description

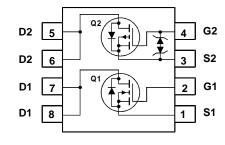
These dual N- and P-Channel enhancement mode power field effect transistors are produced using Fairchild Semiconductor's advanced PowerTrench® process that has been especially tailored to minimize on-state resistance and yet maintain superior switching performance.

These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

Application

- DC-DC Conversion
- BLU and motor drive inverter





MOSFET Maximum Ratings $T_C = 25$ °C unless otherwise noted

Symbol	Parameter			Q1	Q2	Units
V _{DS}	Drain to Source Voltage			30	-30	V
V _{GS}	Gate to Source Voltage			±20	±25	V
1	Drain Current - Continuous	T _A = 25 °C		6.4	-4.5	۸
ID	- Pulsed			30	-30	A
	Power Dissipation for Dual Operation			2	.0	
P_{D}	Power Dissipation for Single Operation	T _A = 25 °C	(Note 1a)	1	.6	W
		T _A = 25 °C	(Note 1b)	0	.9	
E _{AS}	Single Pulse Avalanche Energy (Note 4)		18	5	mJ	
T _J , T _{STG}	Operating and Storage Junction Temperature Range -55 to +150			°C		

Thermal Characteristics

	$R_{\theta JC}$	Thermal Resistance, Junction to Case (No	ote 1)	40	°C/W
Ī	$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note	e 1a)	78	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDS8958B	FDS8958B	SO-8	13 "	12 mm	2500 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Units
Off Chara	cteristics						
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$ $I_D = -250 \mu A, V_{GS} = 0 V$	Q1 Q2	30 -30			V
$\frac{\Delta BV_{DS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C I_D = -250 μA, referenced to 25 °C	Q1 Q2		24 -21		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = -24 \text{ V}, V_{GS} = 0 \text{ V}$	Q1 Q2			1 -1	μА
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$ $V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$	Q1 Q2			±100 ±10	nA μA

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, \ I_D = 250 \ \mu A$ $V_{GS} = V_{DS}, \ I_D = -250 \ \mu A$	Q1 Q2	1.0 -1.0	2.0 -1.9	3.0 -3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25 °C $I_D = -250 \mu A$, referenced to 25 °C	Q1 Q2		-6 5		mV/°C
	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, \ I_D = 6.4 \text{ A}$ $V_{GS} = 4.5 \text{ V}, \ I_D = 5.2 \text{ A}$ $V_{GS} = 10 \text{ V}, \ I_D = 6.4 \text{A}, \ T_J = 125 \text{ °C}$	Q1		21 29 31	26 39 39	m0
r _{DS(on)}	Static Drain to Source On Resistance	V_{GS} = -10 V, I_{D} = -4.5 A V_{GS} = -4.5 V, I_{D} = -3.3 A V_{GS} = -10 V, I_{D} = -4.5 A, T_{J} = 125 °C	Q2		38 60 53	51 80 72	mΩ
g _{FS}	Forward Transconductance	$V_{DD} = 5 \text{ V}, \ I_{D} = 6.4 \text{ A}$ $V_{DD} = -5 \text{ V}, \ I_{D} = -4.5 \text{ A}$	Q1 Q2		20 10		S

Dynamic Characteristics

C _{iss}	Input Capacitance	Q1 V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHZ	Q1 Q2	405 570	540 760	pF
C _{oss}	Output Capacitance	Q2	Q1 Q2	75 115	100 155	pF
C _{rss}	Reverse Transfer Capacitance	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHZ}$	Q1 Q2	55 100	80 150	pF
R _g	Gate Resistance		Q1 Q2	2.4 4.4		Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time	Q1	Q1 Q2	4.3 6.0	10 12	ns
t _r	Rise Time	$V_{DD} = 15 \text{ V}, I_D = 6.4 \text{ A},$ $V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$	Q1 Q2	2.0 6.0	10 12	ns
t _{d(off)}	Turn-Off Delay Time	Q2 V _{DD} = -15 V, I _D = -4.5 A,	Q1 Q2	12 17	22 30	ns
t _f	Fall Time	$V_{GS} = -10 \text{ V}, R_{GEN} = 6 \Omega$	Q1 Q2	2.0 7.0	10 14	ns
Q _{g(TOT)}	Total Gate Charge	V _{GS} = 10 V V _{GS} = -10 V Q1	Q1 Q2	8.3 14	12 19	nC
Q _{g(TOT)}	Total Gate Charge	$V_{GS} = 4.5 \text{ V}$ $V_{GS} = -4.5 \text{ V}$ $V_{DD} = 15 \text{ V}$, $I_D = 6.4 \text{ A}$	Q1 Q2	4.1 7.0	5.8 9.6	nC
Q _{gs}	Gate to Source Charge	Q2 V _{DD} = -15 V,	Q1 Q2	1.3 1.9		nC
Q _{gd}	Gate to Drain "Miller" Charge	$I_D = -4.5 \text{ A}$	Q1 Q2	1.7 3.6		nC

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Parameter

Drain-S	Orain-Source Diode Characteristics					
V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 1.3 \text{ A}$ (Note 2)	Q1	0.8	1.2	V
* SD	Course to Brain Blode 1 of Ward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -1.3 \text{ A}$ (Note 2)	Q2	-0.8	-1.2	•
	Reverse Recovery Time	Q1	Q1	17	30	no
^L rr	Reverse Recovery Time	$I_F = 6.4 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$	Q2	20	36	ns
0	Reverse Recovery Charge	Q2	Q1	6	12	nC
Q _{rr}	Reverse Recovery Charge	$I_F = -4.5 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$	Q2	8	16	IIC

Test Conditions

NOTES

Symbol

1. $R_{\theta,JA}$ is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta,JC}$ is guaranteed by design while $R_{\theta,CA}$ is determined by the user's board design.



a) 78 °C/W when mounted on a 1 in² pad of 2 oz copper



b) 135 °C/W when mounted on a minimun pad

Туре

Min

Тур

Max

Units

- 2. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.
- 3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.
- 4. UIL condition: Starting T_J = 25 °C, L = 1 mH, I_{AS} = 6 A, V_{DD} = 27 V, V_{GS} = 10 V . (Q1)

Starting T_J = 25 °C, L = 1 mH, I_{AS} = -4 A, V_{DD} = -27 V, V_{GS} = -10 V. (Q2)

Typical Characteristics (Q1 N-Channel) T_J = 25 °C unless otherwise noted

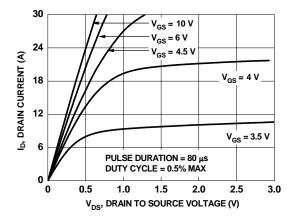
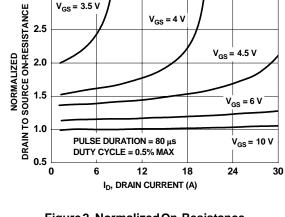


Figure 1. On Region Characteristics



3.0

Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

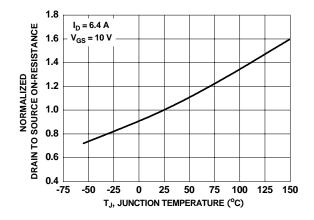


Figure 3. Normalized On Resistance vs Junction Temperature

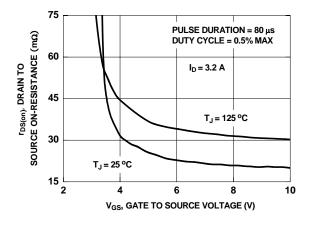


Figure 4. On-Resistance vs Gate to Source Voltage

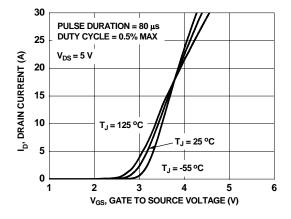


Figure 5. Transfer Characteristics

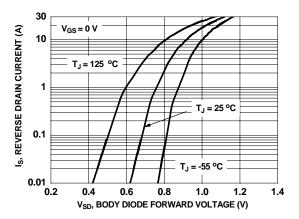


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (Q1 N-Channel) T_J = 25 °C unless otherwise noted

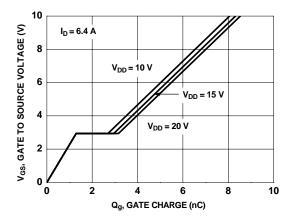


Figure 7. Gate Charge Characteristics

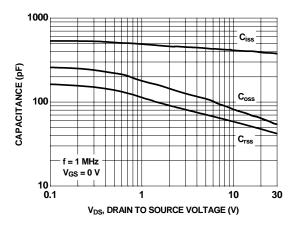


Figure 8. Capacitance vs Drain to Source Voltage

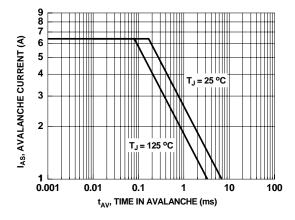


Figure 9. Unclamped Inductive Switching Capability

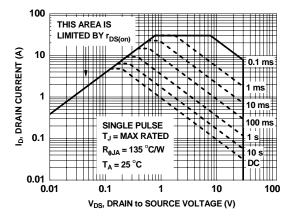


Figure 10. Forward Bias Safe Operating Area

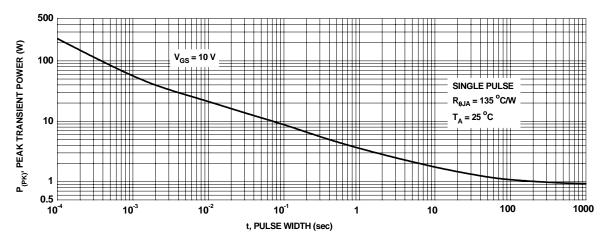


Figure 11. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q1 N-Channel) T_J = 25 °C unless otherwise noted

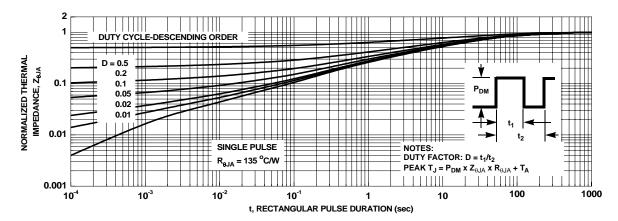


Figure 12. Junction-to-Ambient Transient Thermal Response Curve

Typical Characteristics (Q2 P-Channel) T_J = 25 °C unless otherwise noted

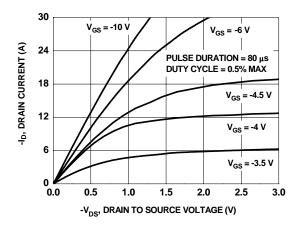


Figure 15. On- Region Characteristics

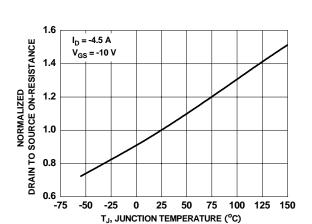


Figure 17. Normalized On-Resistance vs Junction Temperature

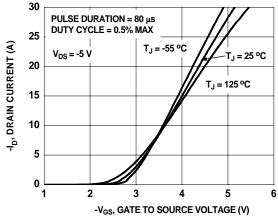


Figure 19. Transfer Characteristics

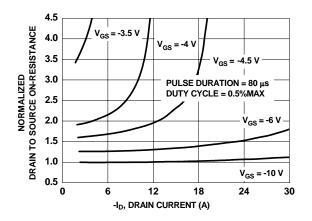


Figure 16. Normalized on-Resistance vs Drain Current and Gate Voltage

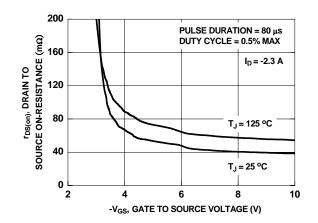


Figure 18. On-Resistance vs Gate to Source Voltage

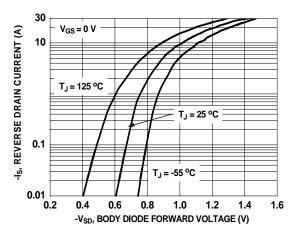


Figure 20. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (Q2 P-Channel) T_J = 25 °C unless otherwise noted

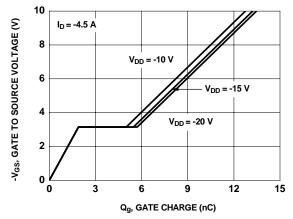


Figure 21. Gate Charge Characteristics

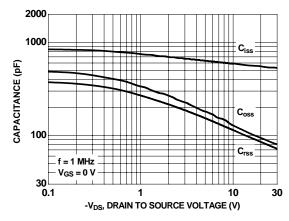


Figure 22. Capacitance vs Drain to Source Voltage

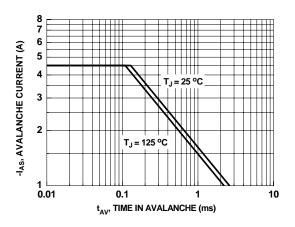


Figure 23. Unclamped Inductive Switching Capability

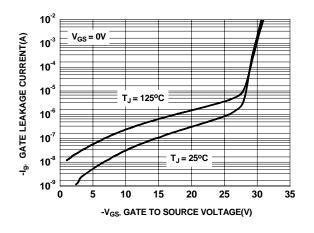


Figure 24. Ig vs Vgs

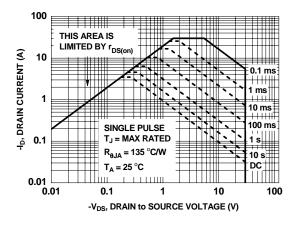


Figure 25. Forward Bias Safe Operating Area

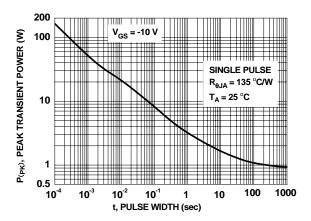


Figure 26. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q2 P-Channel) T_J = 25 °C unless otherwise noted

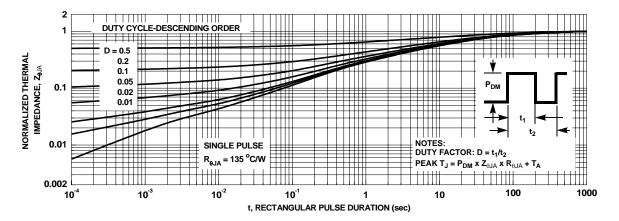


Figure 27. Junction-to-Ambient Transient Thermal Response Curve





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